

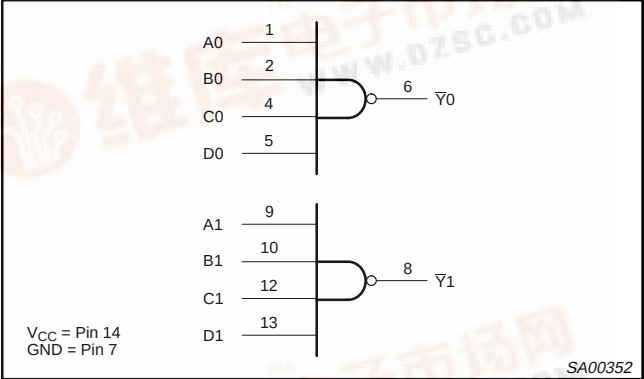
Dual 4-input NAND gate

74ABT20

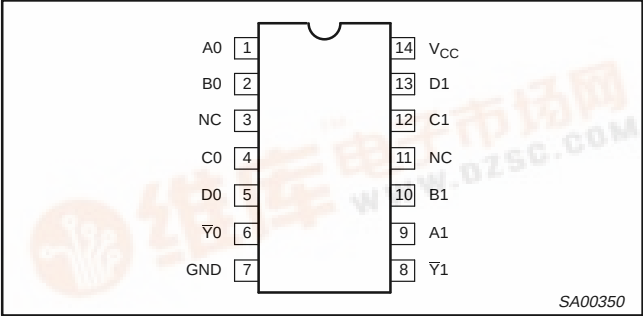
QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS $T_{amb} = 25^{\circ}\text{C}$; $GND = 0V$	TYPICAL	UNIT
t_{PLH} t_{PHL}	Propagation delay A_n, B_n, C_n, D_n to $\bar{Y}_n$	$C_L = 50\text{pF}$; $V_{CC} = 5V$	2.7 2.2	ns
t_{OSLH} t_{OSHL}	Output to Output skew		0.3	ns
C_{IN}	Input capacitance	$V_I = 0V$ or V_{CC}	3	pF
I_{CC}	Total supply current	Outputs disabled; $V_{CC} = 5.5V$	50	μA

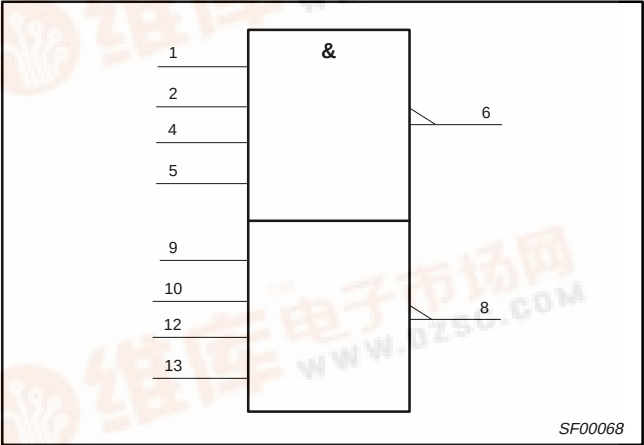
LOGIC DIAGRAM



PIN CONFIGURATION



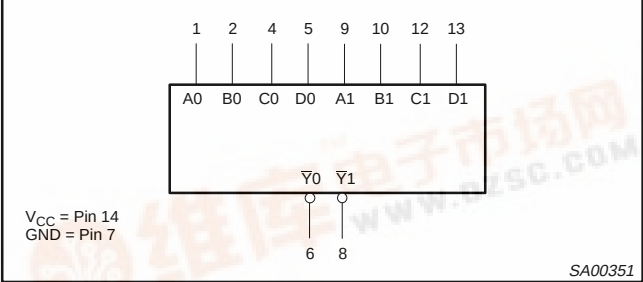
LOGIC SYMBOL (IEEE/IEC)



PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
1, 2, 4, 5, 9, 10, 12, 13	A_n, B_n, C_n, D_n	Data inputs
6, 8	$\bar{Y}_n$	Data outputs
7	GND	Ground (0V)
14	V_{CC}	Positive supply voltage

LOGIC SYMBOL



FUNCTION TABLE

INPUTS				OUTPUT
A_n	B_n	C_n	D_n	$\bar{Y}_n$
L	X	X	X	H
X	L	X	X	H
X	X	L	X	H
X	X	X	L	H
H	H	H	H	L

NOTES:
H = High voltage level
L = Low voltage level
X = Don't care

ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
14-Pin Plastic DIP	-40°C to +85°C	74ABT20 N	74ABT20 N	SOT27-1
14-Pin Plastic SO	-40°C to +85°C	74ABT20 D	74ABT20 D	SOT108-1
14-Pin Plastic SSOP Type II	-40°C to +85°C	74ABT20 DB	74ABT20 DB	SOT337-1
14-Pin Plastic TSSOP Type I	-40°C to +85°C	74ABT20 PW	74ABT20PW DH	SOT402-1

Dual 4-input NAND gate

74ABT20

ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		−0.5 to +7.0	V
I_{IK}	DC input diode current	$V_I < 0$	−18	mA
V_I	DC input voltage ³		−1.2 to +7.0	V
I_{OK}	DC output diode current	$V_O < 0$	−50	mA
V_{OUT}	DC output voltage ³	output in Off or High state	−0.5 to +5.5	V
I_{OUT}	DC output current	output in Low state	40	mA
T_{stg}	Storage temperature range		−65 to 150	°C

NOTES:

- Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.
- The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS		UNIT
		MIN	MAX	
V_{CC}	DC supply voltage	4.5	5.5	V
V_I	Input voltage	0	V_{CC}	V
V_{IH}	High-level input voltage	2.0		V
V_{IL}	Low-level input voltage		0.8	V
I_{OH}	High-level output current		−15	mA
I_{OL}	Low-level output current		20	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	10	ns/V
T_{amb}	Operating free-air temperature range	−40	+85	°C

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS					UNIT
			T _{amb} = +25°C			T _{amb} = −40°C to +85°C		
			MIN	TYP	MAX	MIN	MAX	
V _{IK}	Input clamp voltage	V _{CC} = 4.5V; I _{IK} = −18mA		−0.9	−1.2		−1.2	V
V _{OH}	High-level output voltage	V _{CC} = 4.5V; I _{OH} = −15mA; V _I = V _{IL} or V _{IH}	2.5	2.9		2.5		V
V _{OL}	Low-level output voltage	V _{CC} = 4.5V; I _{OL} = 20mA; V _I = V _{IL} or V _{IH}		0.35	0.5		0.5	V
I _I	Input leakage current	V _{CC} = 5.5V; V _I = GND or 5.5V		±0.01	±1.0		±1.0	μA
I _{OFF}	Power-off leakage current	V _{CC} = 0.0V; V _O or V _I ≤ 4.5V		±5.0	±100		±100	μA
I _{CEX}	Output High leakage current	V _{CC} = 5.5V; V _O = 5.5V; V _I = GND or V _{CC}		5.0	50		50	μA
I _O	Output current ¹	V _{CC} = 5.5V; V _O = 2.5V	−50	−75	−180	−50	−180	mA
I _{CC}	Quiescent supply current	V _{CC} = 5.5V; V _I = GND or V _{CC}		2	50		50	μA
ΔI _{CC}	Additional supply current per input pin ²	V _{CC} = 5.5V; One data input at 3.4V, other inputs at V _{CC} or GND		0.25	500		500	μA

NOTES:

- Not more than one output should be tested at a time, and the duration of the test should not exceed one second.
- This is the increase in supply current for each input at 3.4V.
- For valid test results, data must not be loaded into the flip-flop or latch after applying the power.

Dual 4-input NAND gate

74ABT20

AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5\text{ns}$; $C_L = 50\text{pF}$, $R_L = 500\Omega$

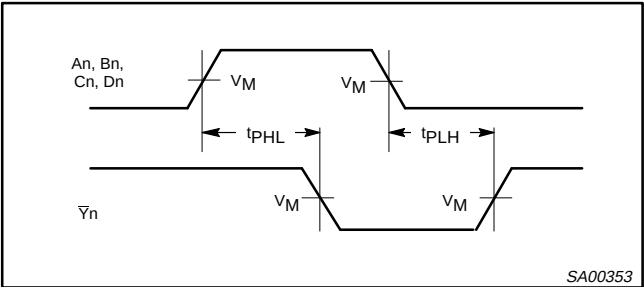
SYMBOL	PARAMETER	WAVEFORM	LIMITS					UNIT
			T _{amb} = +25°C V _{CC} = +5.0V			T _{amb} = -40°C to +85°C V _{CC} = +5.0V ±0.5V		
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay An, Bn, Cn, Dn to $\bar{Y}_n$	1	1.0 1.0	2.7 2.2	3.9 3.4	1.0 1.0	4.6 3.8	ns
t _{OSHL} t _{OSLH} ¹	Output to Output skew An or Bn to $\bar{Y}_n$	2		0.3	0.5		0.5	ns

NOTE:

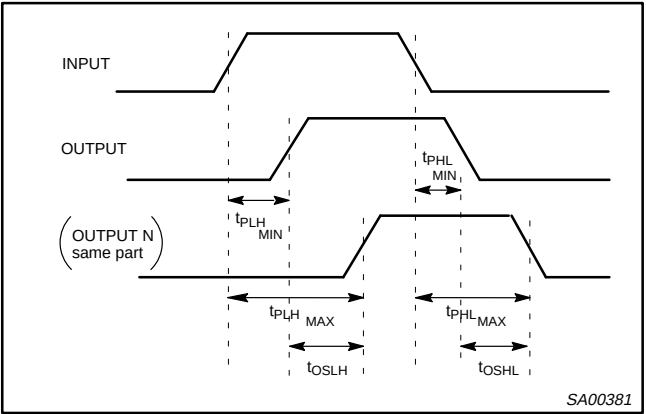
1. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}); parameter guaranteed by design.

AC WAVEFORMS

$V_M = 1.5\text{V}$, $V_{\text{IN}} = \text{GND to } 3.0\text{V}$

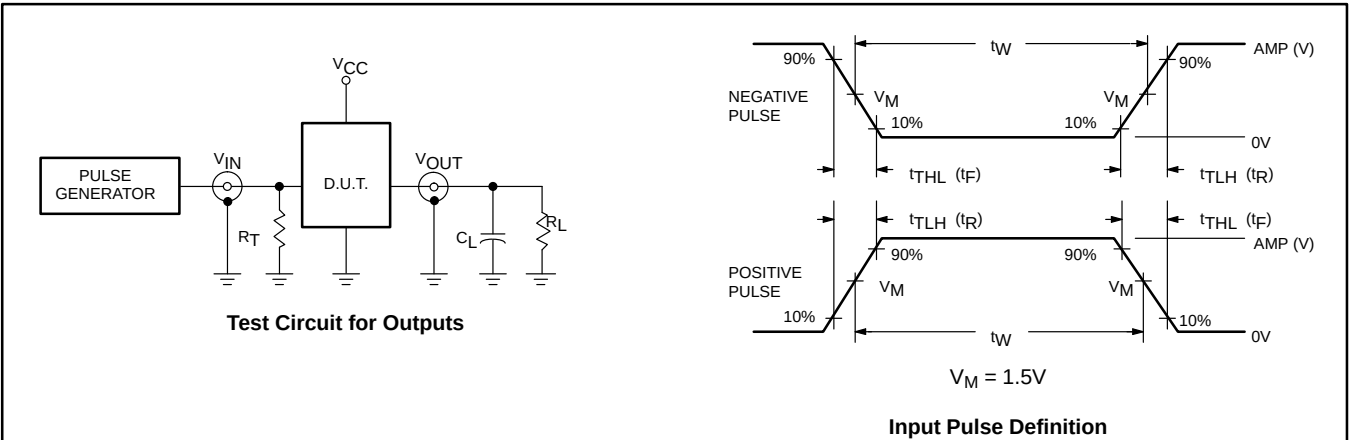


Waveform 1. Propagation Delay for Inverting Outputs



Waveform 2. Common edge skew

TEST CIRCUIT AND WAVEFORMS



DEFINITIONS

- R_L = Load resistor; see AC CHARACTERISTICS for value.
 C_L = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.
 R_T = Termination resistance should be equal to Z_{OUT} of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	t_W	t_R	t_F
74ABT	3.0V	1MHz	500ns	2.5ns	2.5ns